

<b>Notice of References Cited</b>	Application/Control No. 10/541,897	Applicant(s)/Patent Under Reexamination LEE ET AL.
	Examiner Lauren Nguyen	Art Unit 2871

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*	D	US-2001/0035928	11-2001	Kuroiwa et al.	349/115
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**NON-PATENT DOCUMENTS**

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